



**International
Standard**

ISO 23124

**Surface chemical analysis —
Measurement of lateral and axial
resolutions of a Raman microscope**

*Analyse chimique des surfaces — Mesurage des résolutions
latérale et axiale d'un microscope Raman*

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Contents

	Page
Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 General information	1
4.1 Outline of the method.....	1
4.2 Lateral resolution.....	2
4.3 Axial resolution.....	2
5 Sample requirements	3
5.1 Selection of the sample and sample requirement to measure the lateral resolution.....	3
5.2 Selection of the sample and sample requirement to measure the axial resolution.....	3
6 Experimental parameters to be specified	3
6.1 Overview.....	3
6.2 Numerical aperture of objective lens.....	3
6.3 Size of confocal pinhole or the optics which works with similar function.....	4
6.4 Setting the parameters before the operation of the instrument.....	4
7 Data acquisition	5
7.1 Data collection and analysis for lateral resolution.....	5
7.2 Data collection and analysis for axial resolution.....	5
7.3 Recording of the data.....	5
Annex A (informative) Case study using dispersed carbon nanotubes and suspended graphene as samples	7
Bibliography	11

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Foreword

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This document was prepared by Technical Committee ISO/TC 201, *Surface chemical analysis*.

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Introduction

The Raman microscope is usually built on an optical micro-spectroscopy platform and integrated with laser input, laser line filter and spectrometer output. The laser focus is scanned on the sample and the Raman-scattered photons are collected from each pixel to record the full spectrum. Raman spectral images contain a variety of spectral information, such as the intensity, peak position, or peak width of certain Raman bands.

Spatial resolution is one of the main specifications of the Raman microscope. However, the definition and the measurement procedures largely vary depending on the manufacturers of the Raman microscope, therefore the general assessment of the spatial resolution has been limited. In this document, we provide a standardized protocol that describes the measurement of the spatial resolution of a Raman microscope by performing simple measurements using specific standard specimens.

In the Raman microscope, spatial resolution includes the lateral resolution and axial resolution. For this evaluation, there are several methods, such as the straight edge method, narrow line method and grating method. This document describes only the narrow line method for evaluation of the spatial resolution for Raman measurement. A case study of the measurement is provided in [Annex A](#).

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